

P-Ch MOSFET

# **General Description**

The WST3401 is the highest performance trench P-Ch MOSFET with extreme high cell density , which provide excellent RDSON and gate charge for most of the small power switching and load switch applications .

The WST3401 meet the RoHS and Green Product requirement, with full function reliability approved.

#### Features

- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Green Device Available

# **Product Summery**

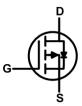
BVDSS	RDSON	ID
-30V	44mΩ	-5.5A

### Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- Load Switch

#### SOT-23-3L Pin Configuration





		Rating		
Symbol	Parameter	10s	Steady State	Units
V <sub>DS</sub>	Drain-Source Voltage	-	-30	
V <sub>GS</sub>	Gate-Source Voltage	±12		V
I <sub>D</sub> @T <sub>C</sub> =25℃	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup>	-6.0	-5.5	А
I <sub>D</sub> @T <sub>C</sub> =70℃	Continuous Drain Current, V <sub>GS</sub> @ -10V <sup>1</sup> -4.9 -4.3		А	
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	-17		А
P₀@T <sub>A</sub> =25℃	Total Power Dissipation <sup>3</sup> 1.32 1		W	
P₀@T <sub>A</sub> =70°C	Total Power Dissipation <sup>3</sup> 0.84		0.64	W
T <sub>STG</sub>	Storage Temperature Range	-55	to 150	°C
TJ	Operating Junction Temperature Range	-55	to 150	°C

### Thermal Data

Symbol	Parameter	Тур.	Max.	Unit
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup>		125	°C/W
R <sub>θJA</sub>	Thermal Resistance Junction-Ambient <sup>1</sup> (t ≤10s)		95	°C/W
R <sub>eJC</sub>	Thermal Resistance Junction-Case <sup>1</sup>		80	°C/W

# **Absolute Maximum Ratings**



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## Electrical Characteristics (T<sub>J</sub>=25<sup>°</sup>C unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	$V_{GS}$ =0V , I <sub>D</sub> =-250uA	-30			V
$\triangle BV_{DSS} / \triangle T_J$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25 $^\circ\!\!{\rm C}$ , I_D=-1mA		-0.023		V/℃
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-10V , I <sub>D</sub> =-3A		44	52	mΩ
		V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-2A		50	58	
V <sub>GS(th)</sub>	Gate Threshold Voltage	V V I 050 A	-0.6		-1.2	V
$ riangle V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	$-V_{GS}=V_{DS}$ , $I_D = -250 uA$		4		mV/℃
	Drain Source Lookage Current	$V_{DS}$ =-24V , $V_{GS}$ =0V , $T_J$ =25 $^{\circ}$ C			-1	uA
I <sub>DSS</sub>	Drain-Source Leakage Current	$V_{\text{DS}}\text{=-}24\text{V}$ , $V_{\text{GS}}\text{=}0\text{V}$ , $T_{\text{J}}\text{=}55^\circ\!\mathrm{C}$			-5	
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ = $\pm$ 12V , $V_{DS}$ =0V			±100	nA
gfs	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-3A		11		S
Qg	Total Gate Charge (-4.5V)	V <sub>DS</sub> =-15V , V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-3A		6.4	9.0	
Q <sub>gs</sub>	Gate-Source Charge			2.3	3.2	nC
Q <sub>gd</sub>	Gate-Drain Charge			1.9	2.7	
T <sub>d(on)</sub>	Turn-On Delay Time			2.8	5.6	
Tr	Rise Time	$V_{DD}\text{=-}15V$ , $V_{GS}\text{=-}10V$ , $R_{G}\text{=}3.3\Omega,$		8.4	15.1	
T <sub>d(off)</sub>	Turn-Off Delay Time	I <sub>D</sub> =-3A		39	78.0	ns
T <sub>f</sub>	Fall Time			6	12.0	
C <sub>iss</sub>	Input Capacitance			583		
Coss	Output Capacitance	$V_{DS}$ =-15V , $V_{GS}$ =0V , f=1MHz		100		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			80		]

#### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
ls	Continuous Source Current <sup>1,4</sup>				-4.3	А
I <sub>SM</sub>	Pulsed Source Current <sup>2,4</sup>	$V_G = V_D = 0V$ , Force Current			-17	А
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	$V_{GS}$ =0V , $I_{S}$ =-1A , $T_{J}$ =25 $^{\circ}$ C			-1	V
trr	Reverse Recovery Time			7.8		nS
Qrr	Reverse Recovery Charge	IF=-3A , dI/dt=100A/µs , T <sub>J</sub> =25 $^\circ \!\!\!\!\!\mathbb{C}$		2.5		nC

Note :

1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper,t<10sec,t<10sec.

2.The data tested by pulsed , pulse width  $\,\leq\,$  300us , duty cycle  $\,\leq\,$  2%

3. The power dissipation is limited by 150  $^\circ\!\mathrm{C}$  junction temperature

4. The data is theoretically the same as  $I_D$  and  $I_{DM}$ , in real applications, should be limited by total power dissipation.



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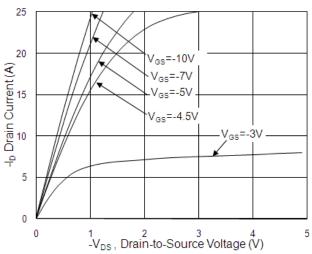


Fig.1 Typical Output Characteristics

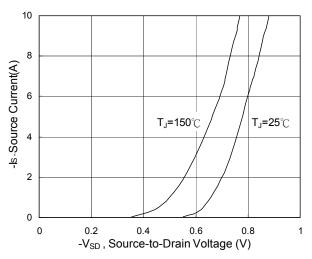
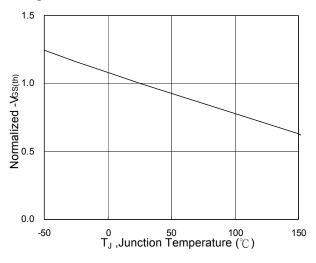


Fig.3 Forward Characteristics of Reverse





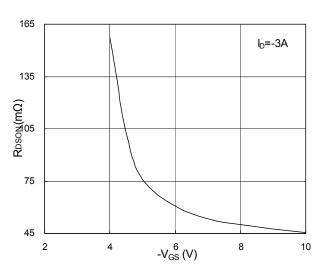


Fig.2 On-Resistance v.s Gate-Source

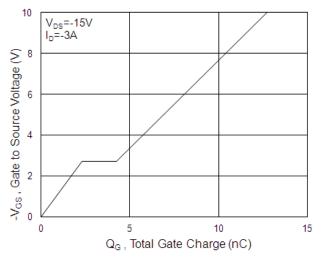
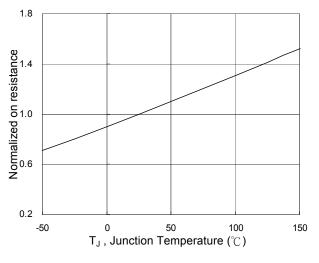
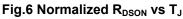


Fig.4 Gate-Charge Characteristics







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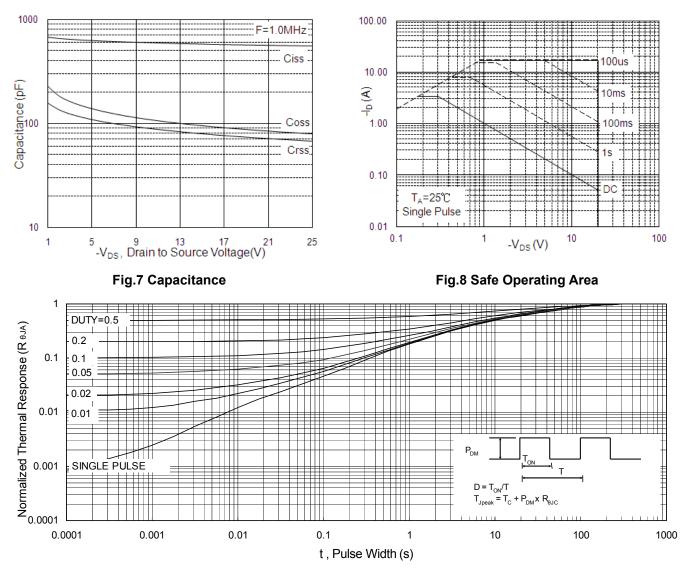
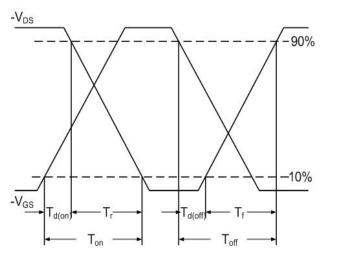
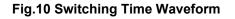
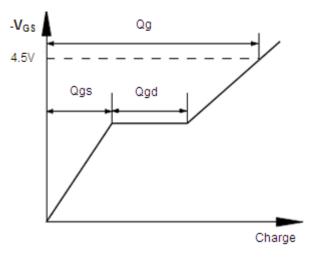


Fig.9 Normalized Maximum Transient Thermal Impedance











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